

<b>Notice of References Cited</b>	Application/Control No. 10/611,422	Applicant(s)/Patent Under Reexamination CHUN, YOUNG-SUN
	Examiner Julian D. Huffman	Art Unit 2853

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	K	US-			
	L	US-			
	M	US-			

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**NON-PATENT DOCUMENTS**

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